

Quarterly Reliability Monitoring Results

Quarters: Q1/2021 to Q4/2021

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory		User Part Number						
		BZB84-C4V7						
		Part Description						
		Nexperia DHAM	Zener					
Assembly reliability labs Based on AEC-Q101 Test		SMD package						
		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
	TEST							
	Pre- and Post-Stress							
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
		JESD22-A113	241					
	PC	Bake Tamb = 125 °C Soak Tamb = 85 °C, RH = 85%	24 hours 168 hours					
# A1	Preconditioning	Reflow soldering	3 cycles	810	58300	0		
		MIL-STD-750-1	-,	010	20300			
	HTRB	M1038 Method A						
	High Temperature Reverse	Tj = Tjmax, Vr = 100% of max. datasheet						
# B1	Bias	reverse voltage	1000 hours	138	11040	0		
		MIL-STD-750-1						
		M1038 Method B						
	SSOP	Tj = Tjmax, $Iz = 100%$ of max. datasheet						
# B1b	Steady State Operational	reverse current	1000 hours	20	1600	0		
		150500 4404						
4 4 4	TC Temperature Cycling	JESD22-A104 -65 °C to Timax, not to exceed 150°C	1000	170	12600	0		
# A4	remperature Cycling		1000 cycles	170	13600	0		
	AC	JESD22-A102 Tamb = 121 °C, RH = 100 %						
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)	96 hours	170	13600	0		
r A3 ait	/ late clave	11055are 205 iii a (2317 pola)	90 Hours	170	13000	0		
	H3TRB	JESD22-A101						
	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of						
# A2 alt	Temperature Reverse Bias	rated reverse voltage ^[1]	1000 hours	170	13600	0		
		MIL-STD-750 Method 1037						
	IOL	ton = toff, devices powered to insure ΔTj =						
# A5	Intermittent Operating Life	100 °C for 15000 cycles	1000 hours	170	13600	0		
	RSH	JESD22-A111						
# C8	Resistance to Solder Heat	260 °C ± 5 °C	10 s	130	3900	0		
" 610	SD Cold and bility	1 CTD 003						
# C10	Solderability	J-STD-002		363	3630	0		

^[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Zener	11040	0	0.38	2.60E+09

^{© 2022} Nexperia B.V.

All information hereunder is per Nexperia's best knowledge. This document does not provide for any representation or warranty express or implied by Nexperia. In case Nexperia has tested the product, this documentation reflects the outcome of the analysis of the actually tested parts only.

nexperia.com